

Search Notes**Application/Control No.**

10/529,742

Examiner

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Applicant(s)/Patent under Reexamination

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Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
438	690	1/22/2007	KCC
438	691		
438	692		
252	79.1		
451	6		
451	41		
451	533	1/22/2007	KCC

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Keywords search USPAT, USPTO-pub. EPO, JPO, Derwent IBM-TDB, inventor search	1/22/2007	KCC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner